

650V Super-Junction Power MOSFET

DESCRIPTION

650V super-junction Power MOSFET

Super-junction power MOSFET is a revolutionary technology for high voltage power MOSFETs, designed according to the SJ principle. The SJ MOSFET is a price-performance optimized product enabling to target cost sensitive applications in Consumer and Lighting markets, designed by Wuxi Unigroup Microelectronics Company.

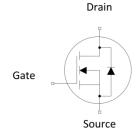
FEATURES

- Very low FOM $R_{DS(on)} \times Q_g$
- 100% avalanche tested
- RoHS compliant

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)







Device Marking and Package Information

Device	Package	Marking
TPW65R090M	TO-247	65R090M

Key Performance Parameters

Parameter	Value	Unit
V _{DS} @ T _{j,max}	650	V
R _{DS(on),max}	0.09	Ω
I _D	47	A
$Q_{g,typ}$	75	nC
I _{DM}	141	A



Absolute Maximum Ratings T _C = 25°C, unless otherwise noted				
Parameter		Symbol	Value	Unit
Drain-Source Voltage (V _{GS} = 0V)		V _{DSS}	650	V
Continuous Drain Current	T _C = 25°C		47	A
Continuous Diam Current	TC = 100°C	l _D	28.2	
Pulsed Drain Current	(note1)	I _{DM}	141	А
Gate-Source Voltage		V _{GSS}	±30	V
Single Pulse Avalanche Energy (note2)		E _{AS}	1160	mJ
Repetitive Avalanche Energy (note2)		E _{AR}	1.76	mJ
Avalanche Current		I _{AR}	9.3	А
MOSFET dv/dt ruggedness, V _{DS} = 0480V		dv/dt	50	V/ns
Power Dissipation		P _D	391	W
Continuous Body Diode Current		I _S	40	A
Pulsed Diode Forward Current (note1)		I _{SM}	141	
Reverse diode dv/dt (note3)		dv/dt	15	V/ns
Maximum diode commutation speed (note3)		di _f /dt	300	A/us
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55~+150	°C

Thermal Resistance			
Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	R _{thJC}	0.32	•c/w
Thermal Resistance, Junction-to-Ambient	R _{thJA}	62	- °C/vv



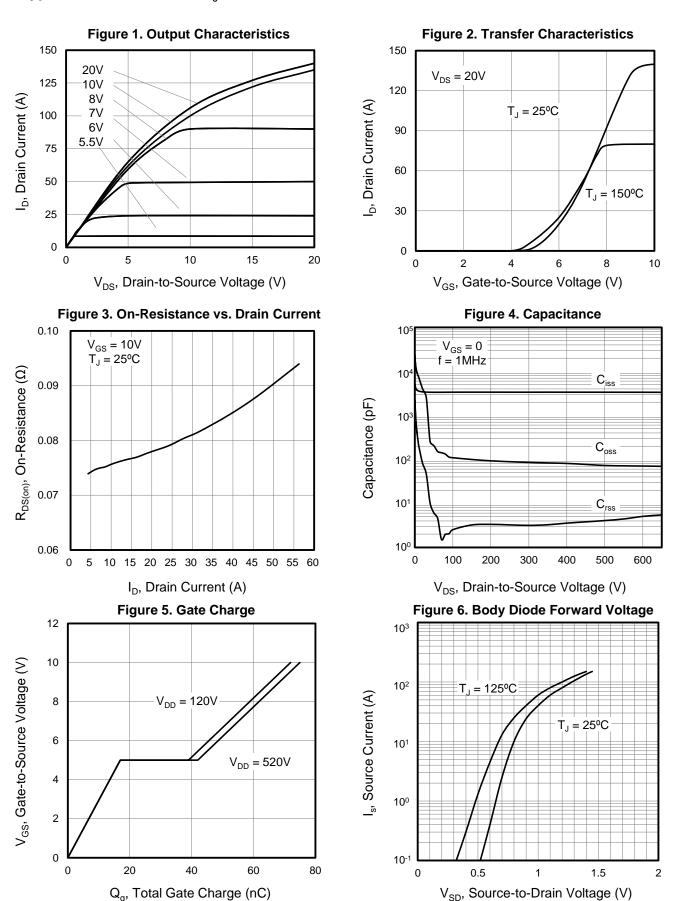
-	nless otherw		Value				
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	!			-	<u> </u>		
Drain-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0V, I_{D} = 250\mu A$	650			V	
		$V_{DS} = 650V, V_{GS} = 0V, T_{J} = 25^{\circ}C$	V _{GS} = 0V, T _J = 25°C		1		
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 650V, V_{GS} = 0V, T_{J} = 150^{\circ}C$			100	μA	
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 30V$			±100	nA	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		4.5	V	
Drain-Source On-Resistance	R _{DS(on)}	V _{GS} = 10V, I _D = 24A		0.079	0.09	Ω	
Gate resistance	R_{G}	f = 1.0MHz open drain		0.8		Ω	
Dynamic	.			!	!		
Input Capacitance	C _{iss}	\/ O\/		3370		pF	
Output Capacitance	C _{oss}	$V_{GS} = 0V,$ $V_{DS} = 100V,$		109			
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		2.5			
Total Gate Charge	Qg			75			
Gate-Source Charge	Q_{gs}	$V_{DD} = 520V, I_{D} = 47A, V_{GS} = 10V$		17		nC	
Gate-Drain Charge	Q_{gd}	65		25			
Turn-on Delay Time	t _{d(on)}			46			
Turn-on Rise Time	t _r	$V_{DD} = 400V, I_{D} = 47A,$		79			
Turn-off Delay Time	t _{d(off)}	$R_G = 25\Omega$		185		ns	
Turn-off Fall Time	t _f			64			
Drain-Source Body Diode Characte	eristics						
Body Diode Voltage	V _{SD}	$T_J = 25^{\circ}C$, $I_{SD} = 24A$, $V_{GS} = 0V$		0.9	1.2	V	
Reverse Recovery Time	t _{rr}			400		ns	
Reverse Recovery Charge	Q _{rr}	$V_R = 400V, I_F = 20A,$ $di_F/dt = 100A/\mu s$		8		μC	
Peak Reverse Recovery Current	I _{rrm}			39.8		Α	

Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. I_{AS} = 9.3A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C
- 3. Identical low side and high side switch with identical $R_{\rm G}$



Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted





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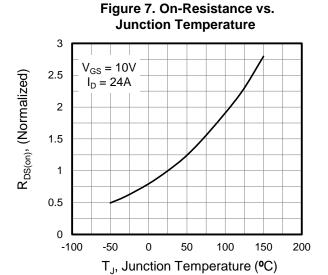


Figure 9. Transient Thermal Impedance for TO-247

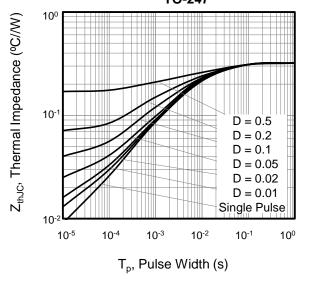


Figure 8. Breakdown voltage vs. Junction Temperature

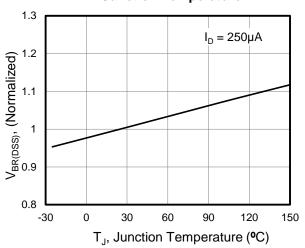
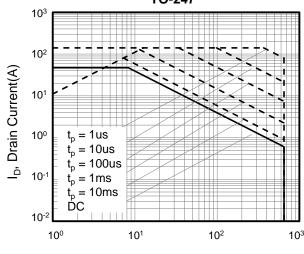


Figure 10. Safe operation area for TO-247



V_{DS}, Drain-Source Voltage(V)



Figure A: Gate Charge Test Circuit and Waveform

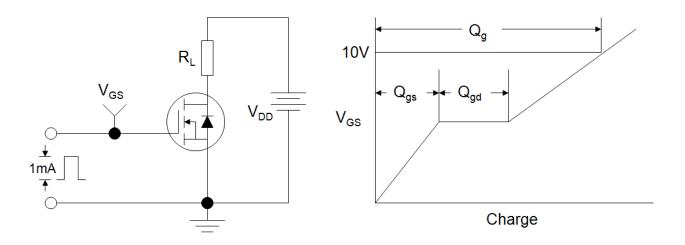


Figure B: Resistive Switching Test Circuit and Waveform

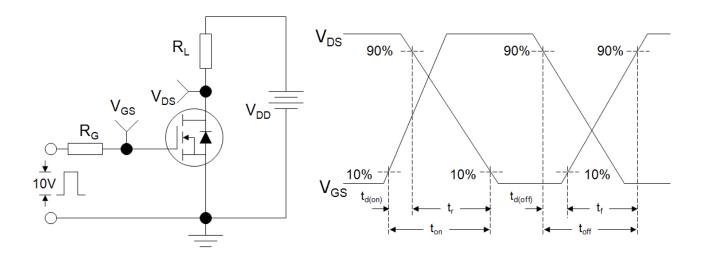
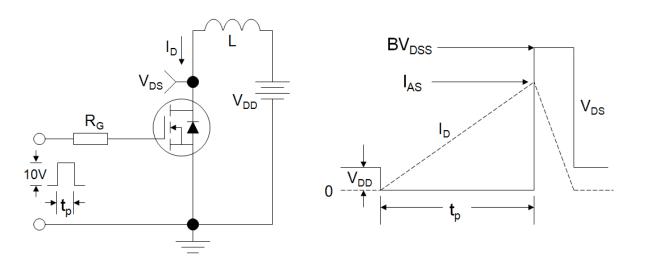


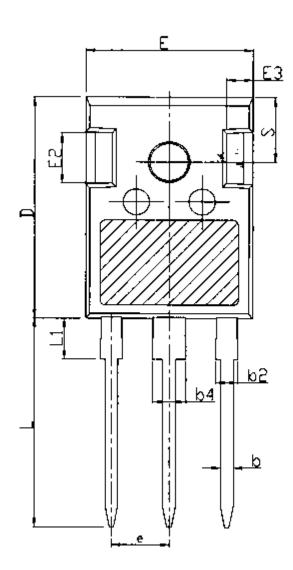
Figure C: Unclamped Inductive Switching Test Circuit and Waveform

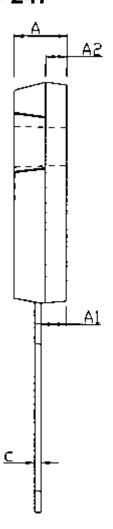


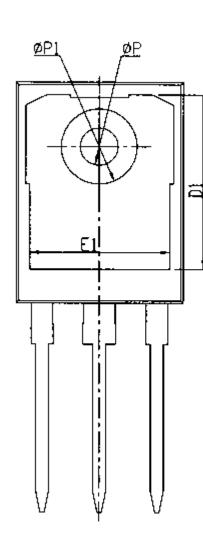




TO-247







Unit:mm					
Symbol	Min.	Nom	Max.		
А	4.80	5.00	5.20		
A1	2.21	2.41	2.61		
A2	1.85	2.00	2.15		
b	1.11	1.21	1.36		
b2	1.91	2.01	2.21		
b4	2.91	3.01	3.21		
С	0.51	0.61	0.75		
D	20.70	21.00	21.30		
D1	16.25	16.55	16.85		

Unit:mm					
Symbol	Min.	Nom.	Max.		
E	15.50	15.80	16.10		
E1	13.00	13.30	13.60		
E2	4.80	5.00	5.20		
E3	2.30	2.50	2.70		
е	5.44BSC				
L	19.62	19.92	20.22		
L1	1	1	4.30		
ΦР	3.40	3.60	3.80		
ФР1	-		7.30		
S		6.15BSC			



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